#### SN54ALS33A, SN74ALS33A QUADRUPLE 2-INPUT POSITIVE-NOR BUFFERS WITH OPEN-COLLECTOR OUTPUTS SDAS034B – APRIL 1982 – REVISED DECEMBER 1994

 Package Options Include Plastic Small-Outline (D) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

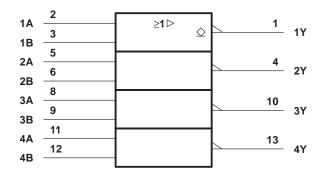
#### description

These devices contain four independent 2-input positive-NOR buffers with open-collector outputs. Open-collector outputs require resistive pullup to perform correctly. They can deliver higher V<sub>OH</sub> levels and commonly are used in wired-AND applications. These devices perform the Boolean functions  $Y = \overline{A} \bullet \overline{B}$  or  $Y = \overline{A + B}$  in positive logic.

The SN54ALS33A is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to 125°C. The SN74ALS33A is characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each gate)							
INP	UTS OUTPUT						
Α	В	Y					
н	Х	L					
Х	Н	L					
L	L	н					

### logic symbol<sup>†</sup>

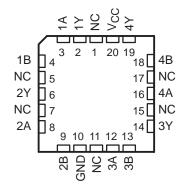


<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, J, and N packages.

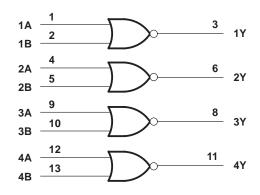
SN54ALS33A J PACKAGE SN74ALS33A D OR N PACKAGE (TOP VIEW)								
1Y [	4	U,						
	1	14	F∧cc					
1A [	2	13	] V <sub>CC</sub> ] 4Y					
1B [	3	12	]4B					
2Y [	4	11	]4A					
2A [	5	10	]3Y					
2B [	6	9	] 3B					
GND [	7	8	13A					

SN54ALS33A . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

#### logic diagram (positive logic)



## SN54ALS33A, SN74ALS33A QUADRUPLE 2-INPUT POSITIVE-NOR BUFFERS WITH OPEN-COLLECTOR OUTPUTS

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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage, V <sub>CC</sub>	
Off-state output voltage	
Operating free-air temperature range, T <sub>A</sub> : SN54ALS33A	
SN74ALS33A	0°C to 70°C
Storage temperature range	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### recommended operating conditions

		SN54ALS33A		SN74ALS33A			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.7			0.8	V
VOH	High-level output voltage			5.5			5.5	V
IOL	Low-level output current			12			24	mA
TA	Operating free-air temperature	-55		125	0		70	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	тес	TEST CONDITIONS		SN54ALS33A			SN74ALS33A		
PARAMETER TEST CONDITIONS		ST CONDITIONS	MIN	MIN TYP <sup>‡</sup> MAX		MIN TYP <sup>‡</sup> MAX		UNIT	
VIK	V <sub>CC</sub> = 4.5 V,	II = -18 mA			-1.5			-1.5	V
Ve	$V_{OL}$ $V_{CC} = 4.5 V$	I <sub>OL</sub> = 12 mA		0.25	0.4		0.25	0.4	V
VOL		I <sub>OL</sub> = 24 mA					0.35	0.5	v
l	V <sub>CC</sub> = 5.5 V,	$V_{I} = 7 V$			0.1			0.1	mA
IIН	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 2.7 V			20			20	μA
١ <sub>IL</sub>	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 0.4 V			-0.1			-0.1	mA
IOH	V <sub>CC</sub> = 4.5 V,	V <sub>OH</sub> = 5.5 V			0.1			0.1	mA
ICCH	V <sub>CC</sub> = 5.5 V,	$V_{I} = 0$		1.7	2.8		1.7	2.8	mA
ICCL	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 4.5 V		5.6	9		5.6	9	mA

<sup>‡</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

#### switching characteristics (see Figure 1)

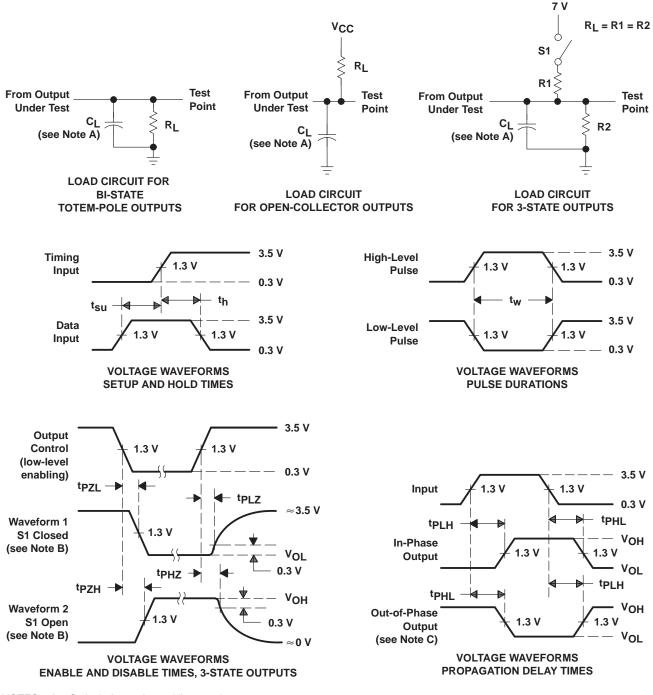
PARAMETER	FROM TO (INPUT) (OUTPUT)	-	VC CL RL TA SN54A	UNIT			
			MIN	MAX	SN74A	MAX	
<sup>t</sup> PLH	A or B	V	10	59	10	33	
<sup>t</sup> PHL		T	2	18	2	12	ns

§ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



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#### PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR  $\leq$  1 MHz, t<sub>r</sub> = t<sub>f</sub> = 2 ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

#### Figure 1. Load Circuits and Voltage Waveforms



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